

Special Issue on
Advances in Optical Measurement Technology for Crack Detection

CALL FOR PAPERS

Optics has become one of the most dynamic fields of science over the past decades. Optical measurements and corresponding processing methods have experienced a significant interest and led to the development and application of several innovations in those fields of optics scientific and engineering research. Academic and research institutions as well as industries have been putting lots of efforts in developing efficient optical measurements for crack detection of many areas, including military, industrial, navigation, aerospace, and even household sectors.

Meanwhile, the corresponding optical processing methods are playing a major role in the design of accurate and reliable image acquisition and recognition. Knowledge and understanding of advanced optical measurements technologies for crack detection have led to the application and development in modern optics. Accordingly, the novel theory and methodology for measurement used in crack detection have provided viable tools to dealing with issues encountered in optical measurement instruments for crack detection.

We invite investigators to contribute original research articles as well as review articles that will stimulate the continuing efforts in various fields of optical technology, photonics, information processing, sensing, and environmental optics. We are particularly interested in articles describing the new methodology and technology in optical measurements technology for crack detection.

Potential topics include but are not limited to the following:

- ▶ Developments in new optical measurement methods and techniques for crack detection
- ▶ Developments in optical imaging processing methods and systems for crack detection
- ▶ Developments in optical computing and information processing for structural health monitoring
- ▶ Novel optical instruments and equipment(including detectors, metrology, sensors, and lasers)
- ▶ Noncontact optical measurement techniques, including optical methods in heat and fluid flow
- ▶ New techniques of optical metrology, including interferometry and optical fiber sensors
- ▶ Other related topics

Authors can submit their manuscripts through the Manuscript Tracking System at <http://mts.hindawi.com/submit/journals/ijo/atmi/>.

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